

FIG. 1 (PRIOR ART)

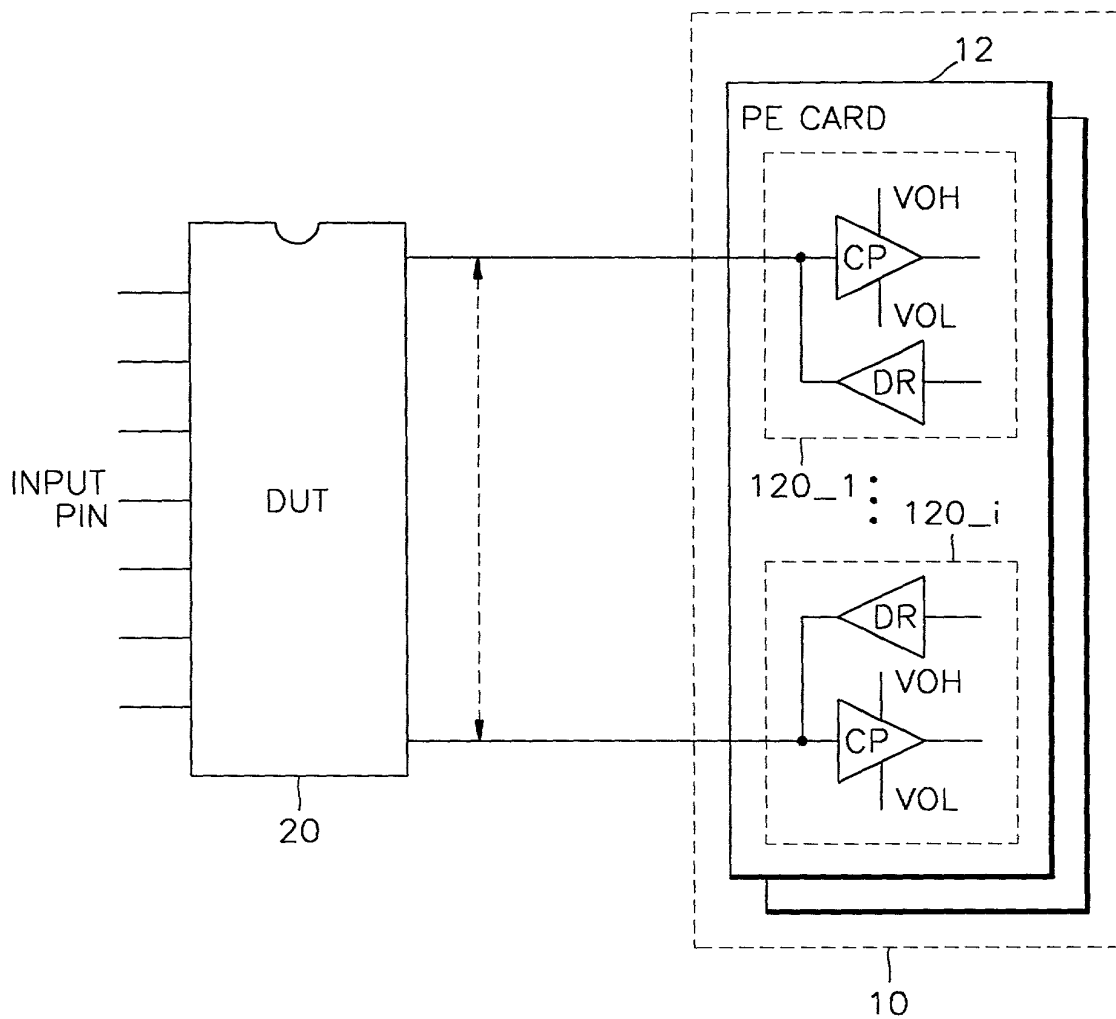
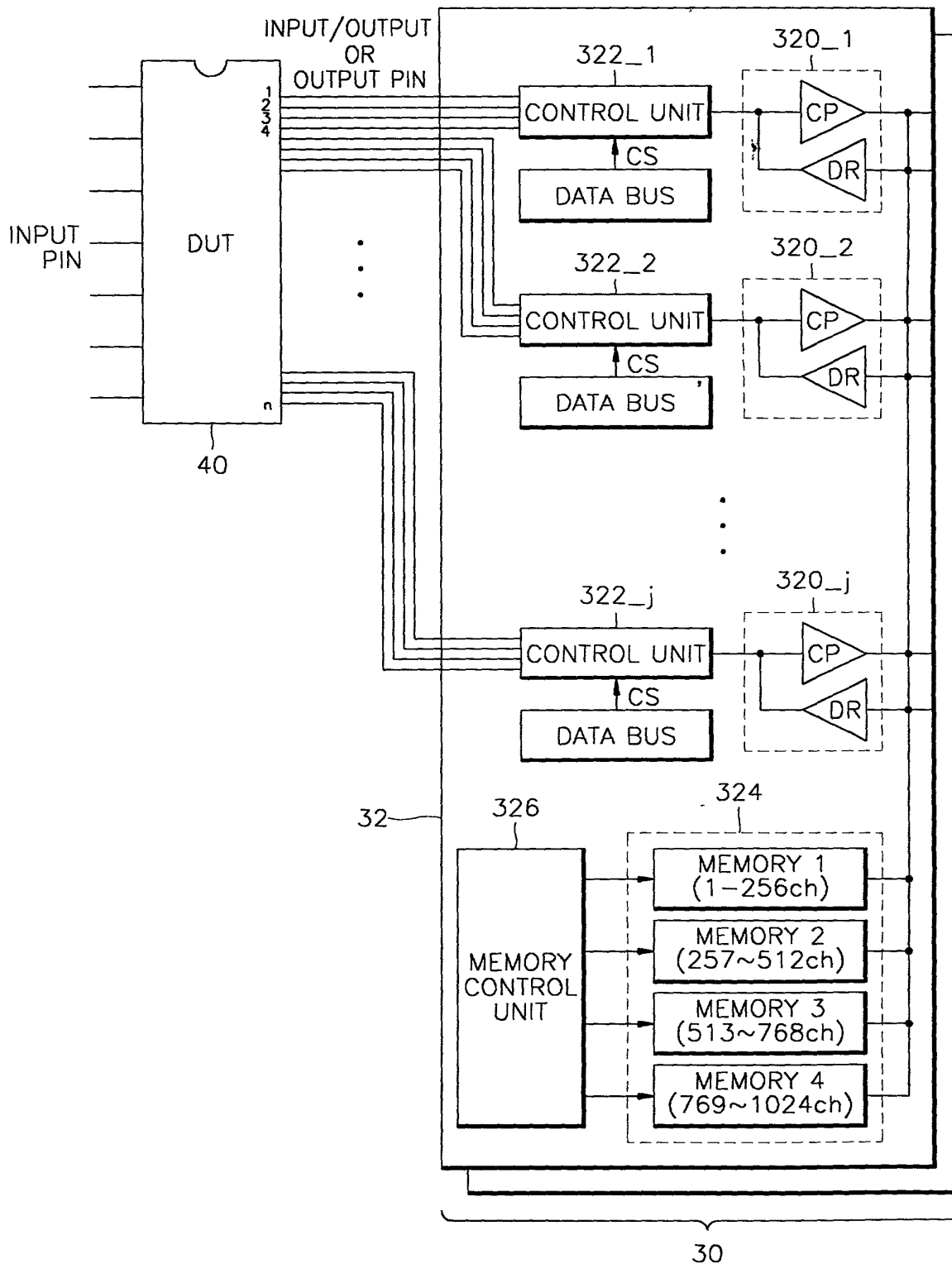


FIG. 2



Inventor: Heon-Deok PARK, et al..

Title: SEMICONDUCTOR TEST SYSTEM AND METHOD
FOR EFFECTIVELY TESTING A SEMICONDUCTOR
DEVICE HAVING MANY PINS

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Page 3 of 5

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FIG. 3 (PRIOR ART)

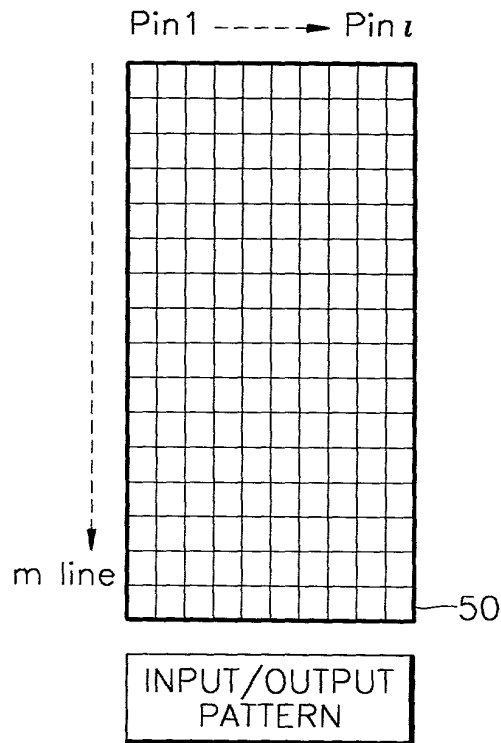


FIG. 4

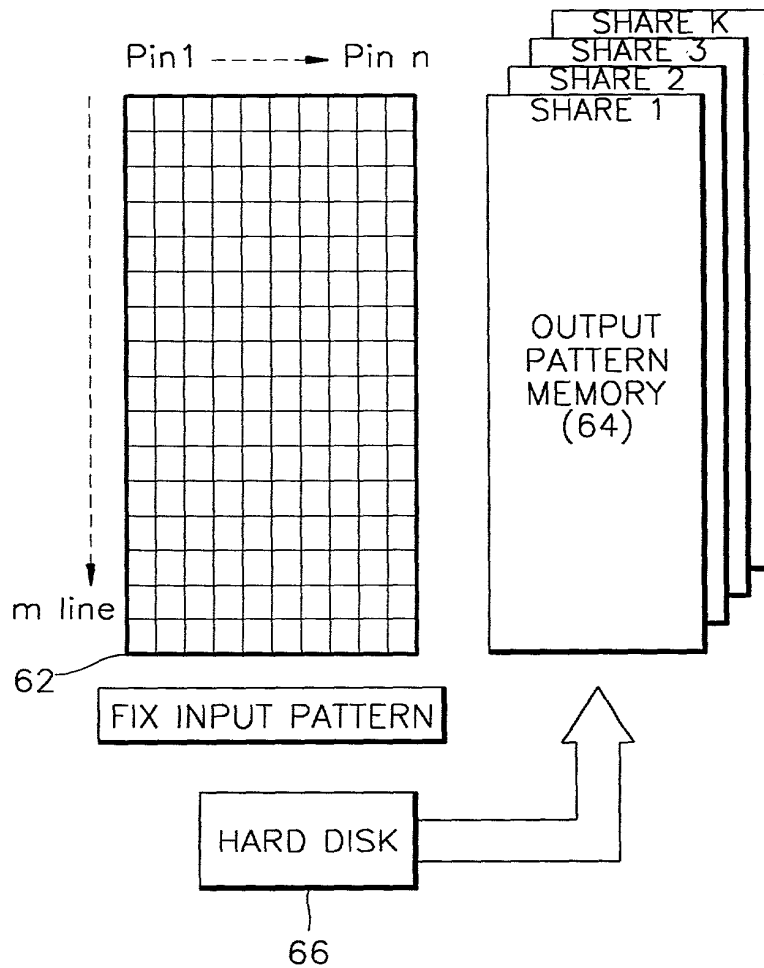


FIG. 5

